# **Power MOSFET**

# 30 V, 127 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVMFS4C05NWF Wettable Flanks Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### **MAXIMUM RATINGS** ( $T_J = 25^{\circ}$ C unless otherwise stated)

Para	meter		Symbol	Value	Unit
Drain-to-Source Volt	Orain-to-Source Voltage		$V_{DSS}$	30	V
Gate-to-Source Volta	age		$V_{GS}$	±20	V
Continuous Drain		T <sub>A</sub> = 25°C		27.2	Α
Current R <sub>0JA</sub> (Notes 1, 2 and 4)		T <sub>A</sub> = 80°C	l <sub>D</sub>	21.6	
Power Dissipation $R_{\theta JA}$ (Notes 1, 2 and 4)		T <sub>A</sub> = 25°C	P <sub>D</sub>	3.61	W
Continuous Drain Current R <sub>0</sub> JC (Notes 1, 2, 3 and 4)	Steady State	T <sub>C</sub> = 25°C		127	
Continuous Drain Current $R_{\theta JC}$ (Notes 1, 2, 3 and 4)		T <sub>C</sub> = 80°C	l <sub>D</sub>	101	А
Power Dissipation $R_{\theta JC}$ (Notes 1, 2, 3 and 4)		T <sub>C</sub> = 25°C	P <sub>D</sub>	79	W
Pulsed Drain Current	$T_A = 25^{\circ}$	$^{\circ}$ C, $t_p = 10 \mu s$	I <sub>DM</sub>	174	Α
Operating Junction ar Temperature	nd Storage		T <sub>J</sub> , T <sub>STG</sub>	-55 to +175	°C
Source Current (Body	/ Diode)		I <sub>S</sub>	72	Α
Single Pulse Drain-to Energy (T <sub>J</sub> = 25°C, I <sub>L</sub>			E <sub>AS</sub>	42	mJ
	ead Temperature for Soldering Purposes //8" from case for 10 s)		TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

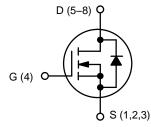
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using 650 mm<sup>2</sup>, 2 oz Cu pad.
- Assumes heat–sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as one second is higher but dependent on pulse duration and duty cycle.



## ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	2.8 m $\Omega$ @ 10 V	127 A
30 V	4.0 mΩ @ 4.5 V	127 A



### **N-CHANNEL MOSFET**



# SO-8 FLAT LEAD CASE 488AA STYLE 1

DIAGRAM

D
S
4C05xx
S
AYWZZ
G
D
D

**MARKING** 

4C05N = Specific Device Code for NVMFS4C05N

4C05WF= Specific Device Code of NVMFS4C05NWF

A = Assembly Location
Y = Year
W = Work Wook

W = Work Week
ZZ = Lot Traceability

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NVMFS4C05NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C05NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel
NVMFS4C05NWFT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C05NWFT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.9	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	41.6	C/VV

<sup>5.</sup> Surface-mounted on FR4 board using 650 mm<sup>2</sup>, 2 oz Cu pad.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				12		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 24 \text{ V}$	$T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$			1.0	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	· ·			±100	nA
ON CHARACTERISTICS (Note 6)		30 1 00			<u> </u>	<u>.                                    </u>	<u>I</u>
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.3		2.2	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>		· · · · · · · · · · · · · · · · · · ·		-5.1		mV/°(
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		2.3	2.8	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		3.3	4.0	
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I	<sub>D</sub> = 15 A		68		S
Gate Resistance	R <sub>G</sub>	T <sub>A</sub> = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES	•						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			1972		pF
Output Capacitance	C <sub>OSS</sub>				1215		
Reverse Transfer Capacitance	C <sub>RSS</sub>				59		
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15 V, f = 1 MHz			0.030		
Total Gate Charge	$Q_{G(TOT)}$				14		<del>                                     </del>
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			3.3		nC
Gate-to-Source Charge	$Q_{GS}$				6.0		
Gate-to-Drain Charge	$Q_{GD}$				5.0		1
Gate Plateau Voltage	$V_{GP}$				3.1		V
Total Gate Charge	$Q_{G(TOT)}$	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			30		nC
SWITCHING CHARACTERISTICS (Note 7	7)				-	-	
Turn-On Delay Time	t <sub>d(ON)</sub>				11		l nc
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$	os = 15 V,		32		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			21		ns
Fall Time	t <sub>f</sub>				7.0		1
Turn-On Delay Time	t <sub>d(ON)</sub>				8.0		
Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			26		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				26		
Fall Time	t <sub>f</sub>				5.0		
DRAIN-SOURCE DIODE CHARACTERIS	TICS		_	_	_	_	
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 V$	T <sub>J</sub> = 25°C		0.77	1.1	V
		I <sub>S</sub> = 10 A	T <sub>J</sub> = 125°C		0.62		
Reverse Recovery Time	t <sub>RR</sub>				40.2		
Charge Time	t <sub>a</sub>	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 30 \text{ A}$			20.3		ns
Discharge Time	t <sub>b</sub>				19.9		
Reverse Recovery Charge	$Q_{RR}$				30.2		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 6. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

<sup>7.</sup> Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**

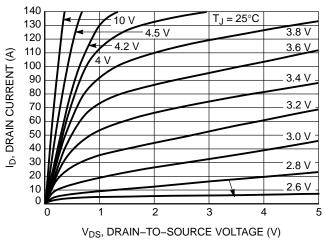


Figure 1. On-Region Characteristics

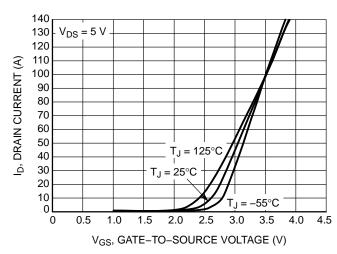


Figure 2. Transfer Characteristics

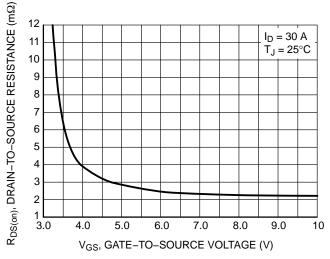


Figure 3. On-Resistance vs. V<sub>GS</sub>

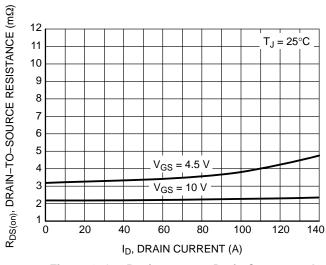


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

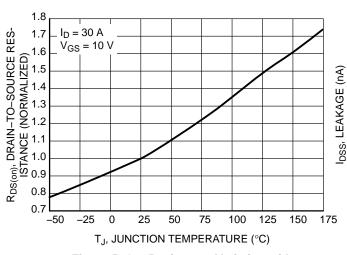


Figure 5. On–Resistance Variation with Temperature

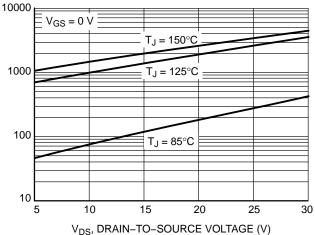


Figure 6. Drain-to-Source Leakage Current vs. Voltage

### **TYPICAL CHARACTERISTICS**

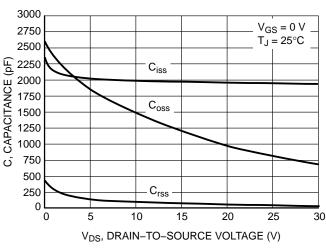


Figure 7. Capacitance Variation

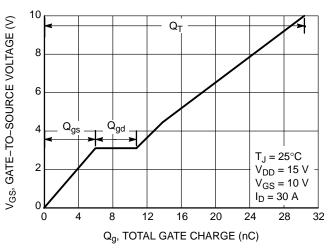


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

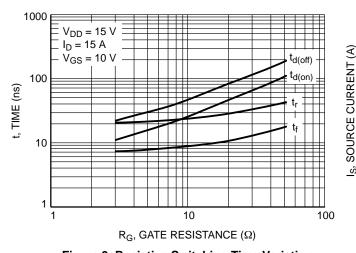


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

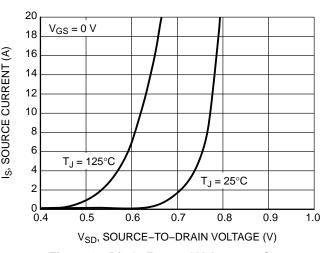


Figure 10. Diode Forward Voltage vs. Current

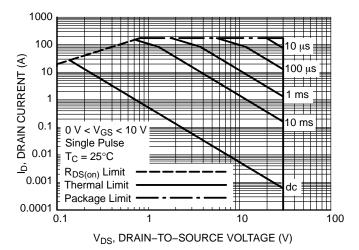


Figure 11. Maximum Rated Forward Biased Safe Operating Area

## **TYPICAL CHARACTERISTICS**

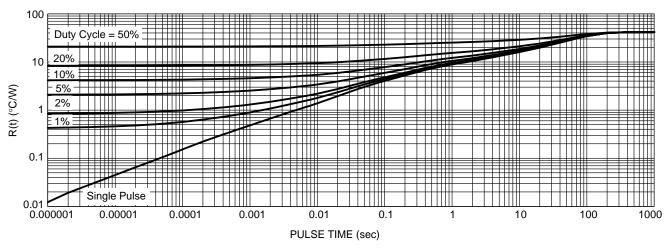


Figure 12. Thermal Response

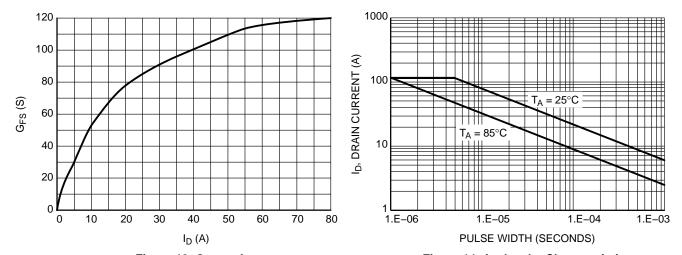
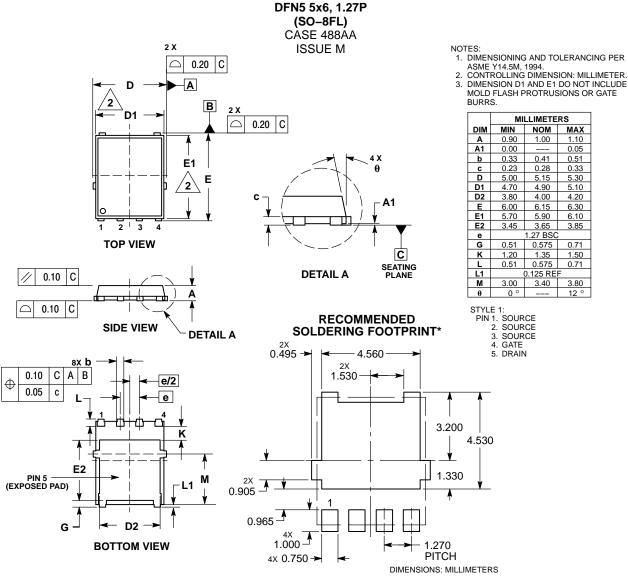


Figure 13.  $G_{FS}$  vs.  $I_D$ 

Figure 14. Avalanche Characteristics

### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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